

# SN54AC00, SN74AC00 QUADRUPLE 2-INPUT POSITIVE-NAND GATES

SCAS524C – AUGUST 1995 – REVISED SEPTEMBER 1996

- **EPIC™ (Enhanced-Performance Implanted CMOS) 1-μm Process**
- **Package Options Include Plastic Small-Outline (D), Shrink Small-Outline (DB), Thin Shrink Small-Outline (PW), DIP (N) Packages, Ceramic Chip Carriers (FK), Flat (W), and DIP (J) Packages**

## description

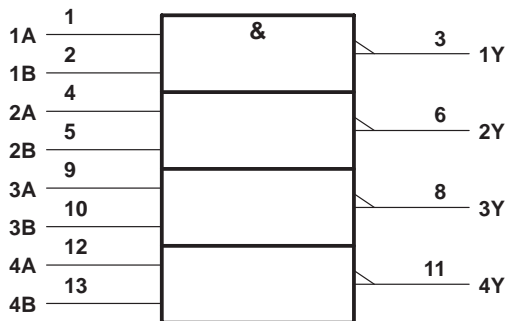
The 'AC00 contain four independent 2-input NAND gates. Each gate performs the Boolean function of  $Y = \overline{A \cdot B}$  or  $Y = \overline{A} + \overline{B}$  in positive logic.

The SN54AC00 is characterized for operation over the full military temperature range of  $-55^{\circ}\text{C}$  to  $125^{\circ}\text{C}$ . The SN74AC00 is characterized for operation from  $-40^{\circ}\text{C}$  to  $85^{\circ}\text{C}$ .

**FUNCTION TABLE**  
(each gate)

INPUTS		OUTPUT
A	B	Y
H	H	L
L	X	H
X	L	H

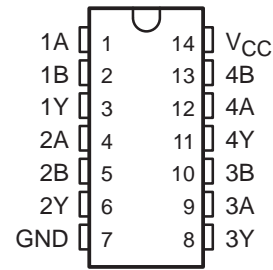
## logic symbol†



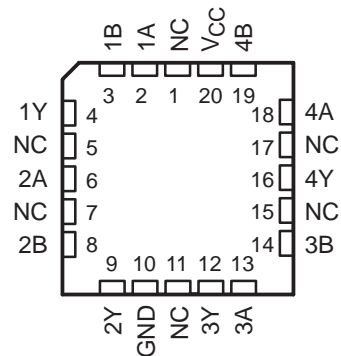
† This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

Pin numbers shown are for the D, DB, J, N, PW, and W packages.

**SN54AC00 . . . J OR W PACKAGE**  
**SN74AC00 . . . D, DB, N, OR PW PACKAGE**  
(TOP VIEW)



**SN54AC00 . . . FK PACKAGE**  
(TOP VIEW)



NC – No internal connection

## logic diagram (positive logic)



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**TEXAS  
INSTRUMENTS**

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SCAS524C – AUGUST 1995 – REVISED SEPTEMBER 1996

## absolute maximum ratings over operating free-air temperature range (unless otherwise noted)†

Supply voltage range, $V_{CC}$	-0.5 V to 7 V
Input voltage range, $V_I$ (see Note 1)	-0.5 V to $V_{CC} + 0.5$ V
Output voltage range, $V_O$ (see Note 1)	-0.5 V to $V_{CC} + 0.5$ V
Input clamp current, $I_{IK}$ ( $V_I < 0$ or $V_I > V_{CC}$ )	$\pm 20$ mA
Output clamp current, $I_{OK}$ ( $V_O < 0$ or $V_O > V_{CC}$ )	$\pm 20$ mA
Continuous output current, $I_O$ ( $V_O = 0$ to $V_{CC}$ )	$\pm 50$ mA
Continuous current through $V_{CC}$ or GND	$\pm 200$ mA
Maximum power dissipation at $T_A = 55^\circ\text{C}$ (in still air) (see Note 2):	
D package	1.25 W
DB package	0.5 W
N package	1.1 W
PW package	0.5 W
Storage temperature range, $T_{stg}$	$-65^\circ\text{C}$ to $150^\circ\text{C}$

† Stresses beyond those listed under “absolute maximum ratings” may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under “recommended operating conditions” is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

- NOTES: 1. The input and output voltage ratings may be exceeded if the input and output current ratings are observed.  
 2. The maximum package power dissipation is calculated using a junction temperature of  $150^\circ\text{C}$  and a board trace length of 750 mils, except for the N package, which has a trace length of zero.

## recommended operating conditions (see Note 3)

		SN54AC00		SN74AC00		UNIT
		MIN	MAX	MIN	MAX	
$V_{CC}$	Supply voltage	2	6	2	6	V
$V_{IH}$	High-level input voltage	$V_{CC} = 3$ V	2.1	2.1		V
		$V_{CC} = 4.5$ V	3.15	3.15		
		$V_{CC} = 5.5$ V	3.85	3.85		
$V_{IL}$	Low-level input voltage	$V_{CC} = 3$ V		0.9	0.9	V
		$V_{CC} = 4.5$ V		1.35	1.35	
		$V_{CC} = 5.5$ V		1.65	1.65	
$V_I$	Input voltage	0	$V_{CC}$	0	$V_{CC}$	V
$V_O$	Output voltage	0	$V_{CC}$	0	$V_{CC}$	V
$I_{OH}$	High-level output current	$V_{CC} = 3$ V		-12	-12	mA
		$V_{CC} = 4.5$ V		-24	-24	
		$V_{CC} = 5.5$ V		-24	-24	
$I_{OL}$	Low-level output current	$V_{CC} = 3$ V		12	12	mA
		$V_{CC} = 4.5$ V		24	24	
		$V_{CC} = 5.5$ V		24	24	
$\Delta t/\Delta v$	Input transition rise or fall rate	0	8	0	8	ns/V
$T_A$	Operating free-air temperature	-55	125	-40	85	$^\circ\text{C}$

NOTE 3: Unused inputs must be held high or low to prevent them from floating.



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SCAS524C – AUGUST 1995 – REVISED SEPTEMBER 1996

**electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)**

PARAMETER	TEST CONDITIONS	V <sub>CC</sub>	T <sub>A</sub> = 25°C			SN54AC00		SN74AC00		UNIT
			MIN	TYP	MAX	MIN	MAX	MIN	MAX	
V <sub>OH</sub>	I <sub>OH</sub> = -50 μA	3 V	2.9			2.9		2.9	V	
		4.5 V	4.4			4.4		4.4		
		5.5 V	5.4			5.4		5.4		
	I <sub>OH</sub> = -12 mA	3 V	2.56			2.4		2.46		
		4.5 V	3.86			3.7		3.76		
	I <sub>OH</sub> = -24 mA	4.5 V	4.86			4.7		4.76		
		5.5 V								
I <sub>OH</sub> = -50 mA†	5.5 V				3.85					
I <sub>OH</sub> = -75 mA†	5.5 V						3.85			
V <sub>OL</sub>	I <sub>OH</sub> = 50 μA	3 V		0.002	0.1		0.1	0.1	V	
		4.5 V		0.001	0.1		0.1	0.1		
		5.5 V		0.001	0.1		0.1	0.1		
	I <sub>OL</sub> = 12 mA	3 V			0.36		0.5	0.44		
		4.5 V			0.36		0.5	0.44		
	I <sub>OL</sub> = 24 mA	4.5 V			0.36		0.5	0.44		
		5.5 V			0.36		0.5	0.44		
I <sub>OL</sub> = 50 mA†	5.5 V					1.65				
I <sub>OL</sub> = 75 mA†	5.5 V						1.65			
I <sub>I</sub>	V <sub>I</sub> = V <sub>CC</sub> or GND	5.5 V			±0.1		±1	±1	μA	
I <sub>CC</sub>	V <sub>I</sub> = V <sub>CC</sub> or GND, I <sub>O</sub> = 0	5.5 V			2		40	20	μA	
C <sub>i</sub>	V <sub>I</sub> = V <sub>CC</sub> or GND	5 V		2.6					pF	

† Not more than one output should be tested at a time, and the duration of the test should not exceed 2 ms.

**switching characteristics over recommended operating free-air temperature range, V<sub>CC</sub> = 3.3 V ± 0.3 V (unless otherwise noted) (see Figure 1)**

PARAMETER	FROM (INPUT)	TO (OUTPUT)	T <sub>A</sub> = 25°C			SN54AC00		SN74AC00		UNIT
			MIN	TYP	MAX	MIN	MAX	MIN	MAX	
t <sub>PLH</sub>	A or B	Y	2	7	9.5	1	11	2	10	ns
t <sub>PHL</sub>			1.5	5.5	8	1	9	1	8.5	

**switching characteristics over recommended operating free-air temperature range, V<sub>CC</sub> = 5 V ± 0.5 V (unless otherwise noted) (see Figure 1)**

PARAMETER	FROM (INPUT)	TO (OUTPUT)	T <sub>A</sub> = 25°C			SN54AC00		SN74AC00		UNIT
			MIN	TYP	MAX	MIN	MAX	MIN	MAX	
t <sub>PLH</sub>	A or B	Y	1.5	6	8	1	8.5	1.5	8.5	ns
t <sub>PHL</sub>			1.5	4.5	6.5	1	7	1	7	

**operating characteristics, V<sub>CC</sub> = 5 V, T<sub>A</sub> = 25°C**

PARAMETER	TEST CONDITIONS	TYP	UNIT
C <sub>pd</sub> Power dissipation capacitance	C <sub>L</sub> = 50 pF, f = 1 MHz	40	pF

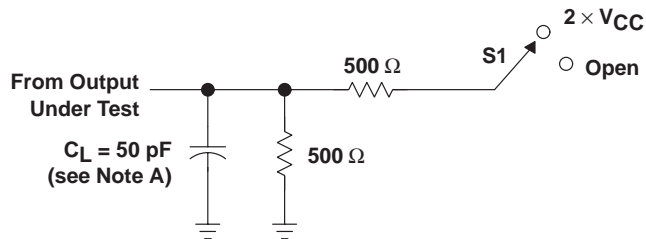


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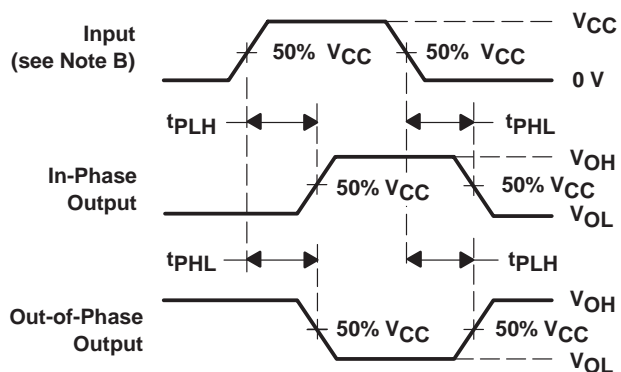
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## PARAMETER MEASUREMENT INFORMATION

TEST	S1
$t_{PLH}/t_{PHL}$	Open



LOAD CIRCUIT



VOLTAGE WAVEFORMS

- NOTES: A.  $C_L$  includes probe and jig capacitance.  
 B. All input pulses are supplied by generators having the following characteristics:  $PRR \leq 1 \text{ MHz}$ ,  $Z_O = 50 \Omega$ ,  $t_r \leq 2.5 \text{ ns}$ ,  $t_f \leq 2.5 \text{ ns}$ .  
 C. The outputs are measured one at a time with one input transition per measurement.

Figure 1. Load Circuit and Voltage Waveforms

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